

<b>Notice of References Cited</b>		Application/Control No. 10/591,695	Applicant(s)/Patent Under Reexamination ILANI ET AL.	
		Examiner TED M. WANG	Art Unit 2611	Page 1 of 1

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*	B	US-2003/0074625	04-2003	Adar et al.	714/752
	C	US-			
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	K	US-			
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	M	US-			

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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.